Notice of References Cited

Application/Control No. 10/689,727	Reexamination	Applicant(s)/Patent Under Reexamination FURUKAWA ET AL.	
Examiner	Art Unit		
Kiet Doan	2683	Page 1 of 1	

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-5,842,131 A	11-1998	Yamane, Kazuyasu	455/456.1.
	8	US-2003/0203723 A1	10-2003	Persson et al.	455/132
	C	US-6,021,125 A	02-2000	Sakoda et al.	370/345
	D	US-6,289,203 B1	09-2001	Smith et al.	455/67.11
	E	US-5,365,571 A	11-1994	Rha et al.	455/446
	F	US-6,553,233 B1	04-2003	Lee et al.	455/446
	G	US-2003/0040317 A1	02-2003	Fattouch, Imad	455/446
	Н	US-2002/0094798 A1	07-2002	Nurminen et al.	455/403
	1	US-6,459,895 B1	10-2002	Hastings et al.	455/424
	J	US-6,064,890 A	05-2000	Hirose et al.	455/513
	К	US-6,154,657 A	11-2000	Grubeck et al.	455/456.2
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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	0					
	Р					
	a					
	R					•
	s					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	v	
	w	
	x	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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